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U.S. Department of Commerce, Patent and Trademark Office	Docket No.		Serial No.		
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	Applicant		Confirmation No.:		
OIPE	Suetter, et al.		9575		
(Use several sheets if necessary) DEC 2 6 2002	Filing Date		Group		
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*Examiner Document Issue Applicant(s) Initial Number Date Applicant(s) Name	Class	Subclass	Filing Date Appropriate		
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Foreign Patent Documents			1		
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B1					
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C3					
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